

20V N-Channel Enhancement-Mode MOSFET

$R_{DS(ON)}, V_{GS}@1.8V, I_{DS}@2.0A = 75m\Omega$

$R_{DS(ON)}, V_{GS}@2.5V, I_{DS}@3.5A = 38m\Omega$

$R_{DS(ON)}, V_{GS}@4.0V, I_{DS}@4.5A = 30m\Omega$

$R_{DS(ON)}, V_{GS}@4.5V, I_{DS}@4.5A = 28m\Omega$

$R_{DS(ON)}, V_{GS}@10V, I_{DS}@5.0A = 25m\Omega$

Features

- Advanced trench process technology
- High Density Cell Design For Ultra Low On-Resistance
- High Power and Current handling capability
- Ideal for Li ion battery pack applications

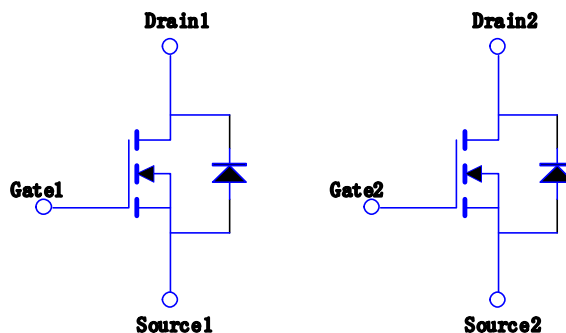
TSSOP-08

SOT-23-6



Top View

Internal Schematic Diagram



N-Channel MOSFET

Maximum Ratings and Thermal Characteristics (T_A = 25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	20	V
Gate-Source Voltage	V _{GS}	±12	
Continuous Drain Current ¹	I _D	6	A
Pulsed Drain Current ²	I _{DM}	20	
Maximum Power Dissipation _B	P _D	2	W
		1.28	
Operating Junction and Storage Temperature Range	T _{j1} T _{stg}	-55 to 150	°C
Junction-to-Ambient Thermal Resistance (PCB mounted) ³	R _{ΘJA}	62.5	°C/W

Note: 1. Fused current that based on wire numbers and diameter

2. Repetitive Rating: Pulse width limited by the maximum junction temperature

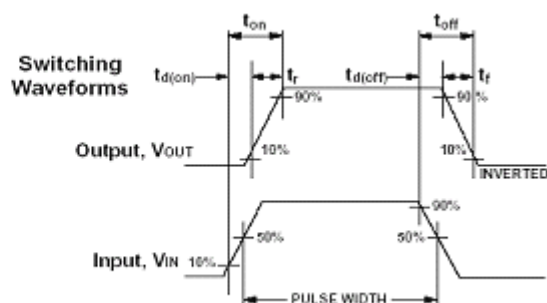
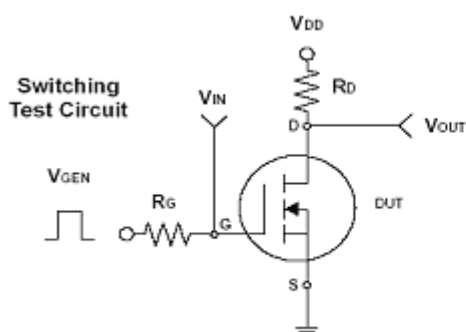
3. 1-in² 2oz Cu PCB board

ELECTRICAL CHARACTERISTICS

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} = 0V,I _D = 250uA	20			V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} = 1.8V,I _D = 2.0A		53.0	75.0	mΩ
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} = 2.5V,I _D = 3.5A		30.0	38.0	
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} = 4.0V,I _D = 4.5A		23.0	30.0	
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} = 4.5V,I _D = 4.5A		22.0	28.0	
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} = 10V,I _D = 5.0A		20.0	25.0	
Gate Threshold Voltage	V _{GS(th)}	V _{GS} = V _{GS} ,I _D = 250uA	0.5	0.75	1	V
Zero Gate Voltage drain Current	I _{DSS}	V _{GS} = 20V,V _{GS} = 0V			1	uA
Gate Body Leakage	I _{GSS}	V _{GS} = ±12V,V _{DS} = 0V			±100	nA
Dynamic ³						
Total Gate Charge	Q _G	V _{DS} = 10V,I _D = 6A V _{GS} = 4.5V		6.24	8.11	nC
Gate-Source Charge	Q _{GS}			1.64	2.13	
Gate-Drain Charge	Q _{GB}			1.34	1.74	
Tum-On Delay Time	T _{d(on)}	V _{DD} = 10V,I _D = 6A I _D = 1A,V _{GS} = 4.5V		10.4	20.8	ns
Tum-On Rise Time	T _r			4.4	8.8	
Tum-Off Delay Time	T _{d(off)}			27.36	54.72	
Tum-Off Fall Time	T _f			4.16	8.32	
Input Capacitance	C _{iss}	V _{DS} = 8V,V _{GS} = 0V f=1.0MHz		522.3		pF
Output Capacitance	C _{oss}			98.48		
Reverse Transfer Capacitance	C _{rss}			74.69		
Source-Drain Diode						
Max.Diode Forward Current	I _s				1.7	A
Diode Forward Voltage	V _{SD}	I _s = 1.7A,V _{GS} = 0V		0.74		V

Note: Pulse test: pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$

3. Guaranteed by design; not subject to production testing



Typical Characteristics Curves ($T_a=25^\circ\text{C}$, unless otherwise note)

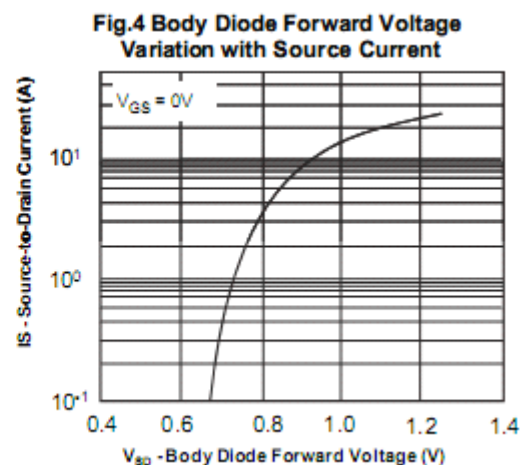
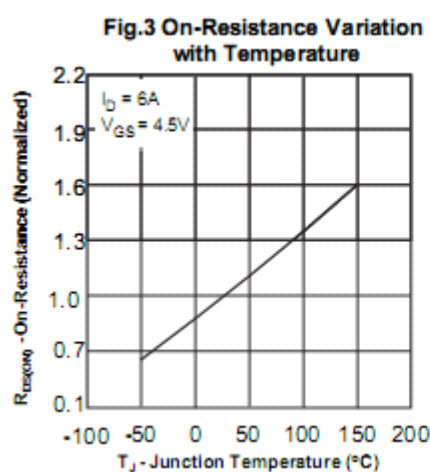
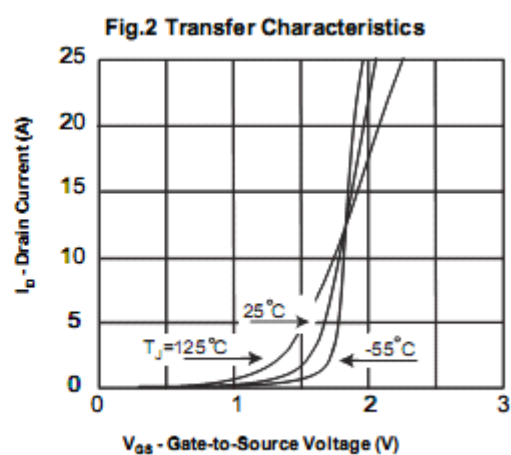
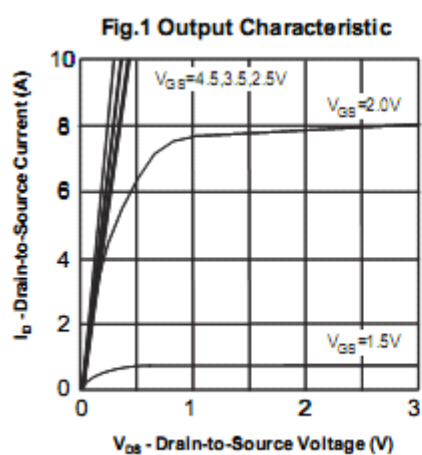


Fig.5 Gate Threshold Variation with Temperature

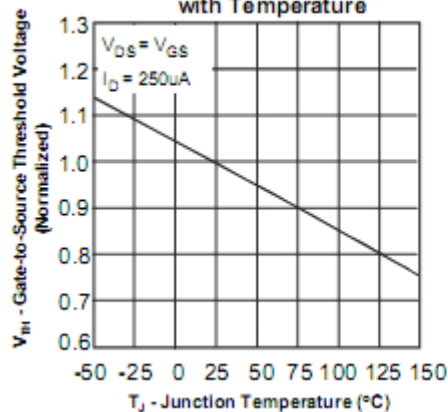


Fig.6 Capacitance

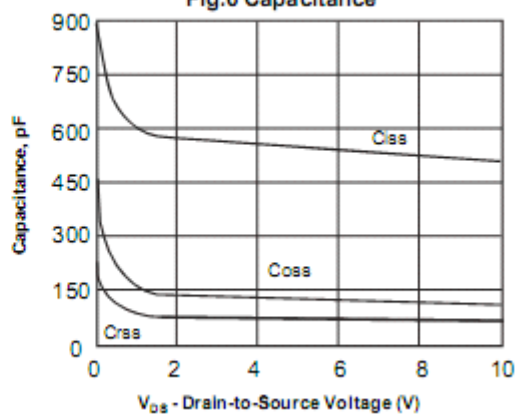


Fig. 7 Gate Charge Waveform

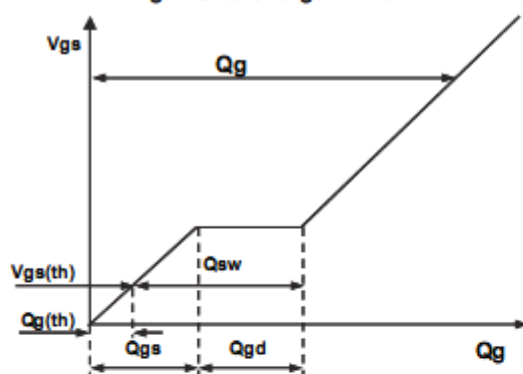


Fig. 8 Gate Charge

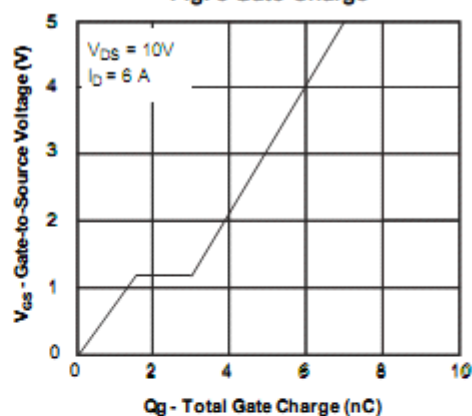


Fig. 9 Maximum Safe Operating Area

